

## N - CHANNEL ENHANCEMENT MODE POWER MOS TRANSISTOR

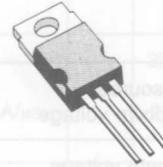
TYPE	V <sub>DSS</sub>	R <sub>DS(on)</sub>	I <sub>D</sub>
BUZ76A	400 V	2.5 Ω	2.6 A

- HIGH VOLTAGE - FOR OFF-LINE APPLICATIONS
- ULTRA FAST SWITCHING
- EASY DRIVE - FOR REDUCED COST AND SIZE

### INDUSTRIAL APPLICATIONS:

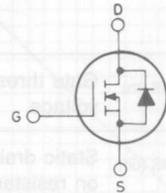
- ELECTRONIC LAMP BALLAST
- DC SWITCH

N - channel enhancement mode POWER MOS field effect transistor. Easy drive and very fast switching times make this POWER MOS transistor ideal for high speed switching applications. Applications include off-line use, constant current source, ultrasonic equipment and switching power supply start-up circuits.



TO-220

### INTERNAL SCHEMATIC DIAGRAM



### ABSOLUTE MAXIMUM RATINGS

V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	400	V
V <sub>DGR</sub>	Drain-gate voltage (R <sub>GS</sub> = 20 KΩ)	400	V
V <sub>GS</sub>	Gate-source voltage	±20	V
I <sub>D</sub>	Drain current (continuous) T <sub>c</sub> = 30°C	2.6	A
I <sub>DM</sub>	Drain current (pulsed)	10	A
P <sub>tot</sub>	Total dissipation at T <sub>c</sub> < 25°C	40	W
T <sub>stg</sub>	Storage temperature	-55 to 150	°C
T <sub>j</sub>	Max. operating junction temperature	150	°C
	DIN humidity category (DIN 40040)	E	
	IEC climatic category (DIN IEC 68-1)	55/150/56	

## THERMAL DATA

$R_{thj-case}$	Thermal resistance junction-case	max	3.1	$^{\circ}\text{C}/\text{W}$
$R_{thj-amb}$	Thermal resistance junction-ambient	max	75	$^{\circ}\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ( $T_J = 25^{\circ}\text{C}$  unless otherwise specified)

Parameters	Test Conditions	Min.	Typ.	Max.	Unit
------------	-----------------	------	------	------	------

## OFF

$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 250 \mu\text{A}$	$V_{GS} = 0$	400		V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max Rating}$	$T_J = 125^{\circ}\text{C}$		250 1000	$\mu\text{A}$ $\mu\text{A}$
$I_{GSS}$	Gate-body leakage current ( $V_{DS} = 0$ )	$V_{GS} = \pm 20 \text{ V}$			$\pm 100$	nA

## ON

$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}$	$I_D = 1 \text{ mA}$	2.1	4	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10 \text{ V}$	$I_D = 1.5 \text{ A}$		2.5	$\Omega$

## DYNAMIC

$g_{fs}$	Forward transconductance	$V_{DS} = 25 \text{ V}$	$I_D = 1.5 \text{ A}$	0.8		mho
$C_{iss}$	Input capacitance				500	pF
$C_{oss}$	Output capacitance	$V_{DS} = 25 \text{ V}$	$f = 1 \text{ MHz}$		80	pF
$C_{rss}$	Reverse transfer capacitance	$V_{GS} = 0$			60	pF

## SWITCHING

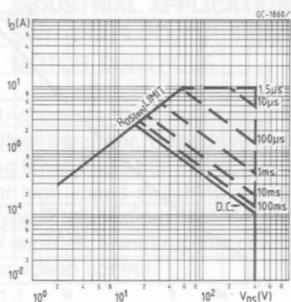
$t_d(on)$	Turn-on time	$V_{DD} = 30 \text{ V}$	$I_D = 2.4 \text{ A}$		20	ns
$t_r$	Rise time	$R_{GS} = 50 \Omega$	$V_{GS} = 10 \text{ V}$		60	ns
$t_d(off)$	Turn-off delay time				65	ns
$t_f$	Fall time				40	ns

ELECTRICAL CHARACTERISTICS (Continued)

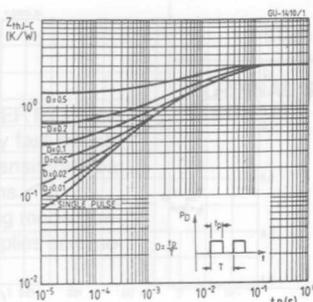
Parameters		Test Conditions		Min.	Typ.	Max.	Unit
$I_{SD}$	Source-drain current	$T_c = 25^\circ\text{C}$				2.6	A
$I_{SDM}$	Source-drain current (pulsed)					10	A
$V_{SD}$	Forward on voltage	$I_{SD} = 5.2\text{ A}$	$V_{GS} = 0$			1.4	V
$t_{rr}$	Reverse recovery time	$I_{SD} = 2.6\text{ A}$	$di/dt = 100\text{A}/\mu\text{s}$		300		ns
$Q_{rr}$	Reverse recovered charge				2.5		$\mu\text{C}$

SOURCE DRAIN DIODE

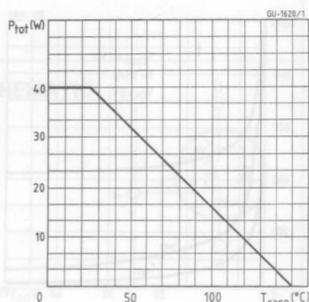
Safe operating areas



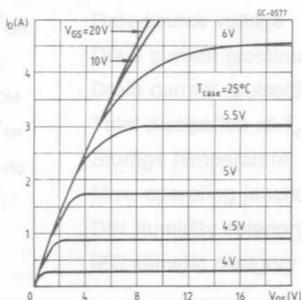
Thermal impedance



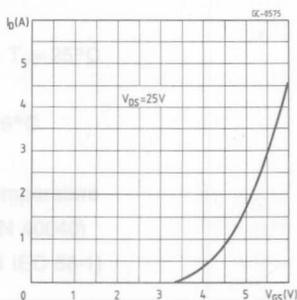
Derating curve



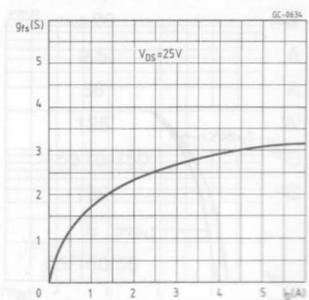
Output characteristics



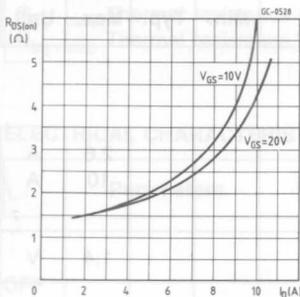
Transfer characteristics



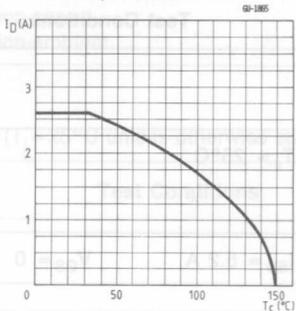
Transconductance



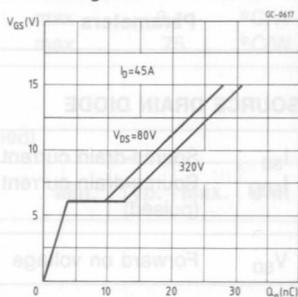
Static drain-source on resistance



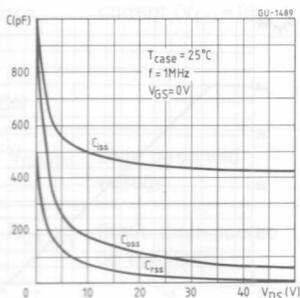
Maximum drain current vs temperature



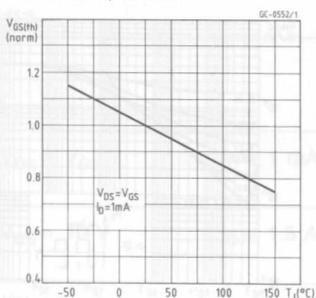
Gate charge vs gate-source voltage



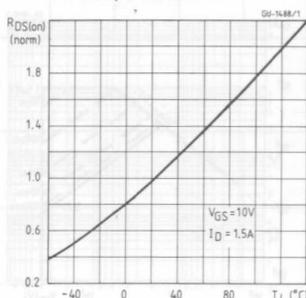
Capacitance variation



Gate threshold voltage vs temperature



Drain-source on resistance vs temperature



Source-drain diode forward characteristics

